

L Number	Hits	Search Text	DB	Time stamp
1	3042	azomono chlorosilane) or amcs or (azomono chloro adj1 silane) or (azomono adj1 chloro adj1 silane)	USPAT; US-PGPUB	2004/08/20 08:05
2	33	trench and (azomono chlorosilane) or amcs or (azomono chloro adj1 silane) or (azomono adj1 chloro adj1 silane))	USPAT; US-PGPUB	2004/08/20 07:22
3	2433	(groove or opening or via or hole or viahole or trench) and (azomono chlorosilane) or amcs or (azomono chloro adj1 silane) or (azomono adj1 chloro adj1 silane))	USPAT; US-PGPUB	2004/08/20 08:05
4	2433	(groove or opening or via or hole or viahole or trench) and (azomono chlorosilane) or amcs or (azomono chloro adj1 silane) or (azomono adj1 chloro adj1 silane))	USPAT; US-PGPUB	2004/08/20 07:23
6	1500	((groove or opening or via or hole or viahole or trench) and (azomono chlorosilane) or amcs or (azomono chloro adj1 silane) or (azomono adj1 chloro adj1 silane))) and (polymer or polymeri\$)	USPAT; US-PGPUB	2004/08/20 07:29
7	1392	((groove or opening or via or hole or viahole or trench) and (azomono chlorosilane) or amcs or (azomono chloro adj1 silane) or (azomono adj1 chloro adj1 silane))) and (polymer or polymeri\$)) and (radiat\$ or uv or light or laser or irradiat\$)	USPAT; US-PGPUB	2004/08/20 07:29
8	1408080	photoresist\$ or resist\$	USPAT; US-PGPUB	2004/08/20 07:30
9	1193	((((groove or opening or via or hole or viahole or trench) and (azomono chlorosilane) or amcs or (azomono chloro adj1 silane) or (azomono adj1 chloro adj1 silane))) and (polymer or polymeri\$)) and (radiat\$ or uv or light or laser or irradiat\$)) and (photoresist\$ or resist\$)	USPAT; US-PGPUB	2004/08/20 07:30
10	158	(groove or opening or via or hole or viahole or trench) same (azomono chlorosilane) or amcs or (azomono chloro adj1 silane) or (azomono adj1 chloro adj1 silane))	USPAT; US-PGPUB	2004/08/20 07:33
11	451	azomono chlorosilane) or amcs or (azomono chloro adj1 silane) or (azomono adj1 chloro adj1 silane)	EPO; JPO; DERWENT; IBM_TDB	2004/08/20 08:07
12	14	(groove or opening or via or hole or viahole or trench) same (azomono chlorosilane) or amcs or (azomono chloro adj1 silane) or (azomono adj1 chloro adj1 silane))	EPO; JPO; DERWENT; IBM_TDB	2004/08/20 07:31
13	3042	azomono chlorosilane) or "amcs" or (azomono chloro adj1 silane) or (azomono adj1 chloro adj1 silane)	USPAT; US-PGPUB	2004/08/20 07:32
14	158	(groove or opening or via or hole or viahole or trench) same (azomono chlorosilane) or "amcs" or (azomono chloro adj1 silane) or (azomono adj1 chloro adj1 silane))	USPAT; US-PGPUB	2004/08/20 08:26

16	1	azomono chlorosilane or (azomono adj1 chlorosilane) or (azomono chloro adj1 silane) or (azomono adj1 chloro adj1 silane)	USPAT; US-PGPUB	2004/08/20 08:21
17	1	(groove or opening or via or hole or viahole or trench) and (azomono chlorosilane or (azomono adj1 chlorosilane) or (azomono chloro adj1 silane) or (azomono adj1 chloro adj1 silane))	USPAT; US-PGPUB	2004/08/20 08:06
18	0	azomono chlorosilane or (azomono adj1 chlorosilane) or (azomono chloro adj1 silane) or (azomono adj1 chloro adj1 silane)	EPO; JPO; DERWENT; IBM_TDB	2004/08/20 08:07

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